## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | MALTSEV ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0110184 A1	08-2002	Akopian et al.	375/149
*	В	·US-2002/0181390 A1	12-2002	Mody et al.	370/208
*	С	US-2003/0118094 A1	06-2003	Wang et al.	375/231
*	D	US-2003/0152021 A1	08-2003	Wang et al.	370/208
*	Е	US-6,608,863 B1	08-2003	Onizawa et al.	375/232
*	F	US-2004/0042545 A1	03-2004	Han et al.	375/232
*	G	US-2004/0142665 A1	07-2004	Papathanasion et al.	455/101
*	Н	US-2004/0125235 A1	07-2004	Kim et al.	348/607
*	1	US-2005/0026565 A1	02-2005	Goldstein et al.	455/067.11
*	J	US-2005/0152314 A1	07-2005	Sun et al.	370/334
*	К	US-2006/0227904 A1	10-2006	Mueller-Weinfurtner et al.	375/343
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0	•		y		-
	Р				-	
	Q					
	R					
	s	al .				
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	Sun et al., Specification of Provisional Application 60/517,445, 11/4/2003
	v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.